## Preliminary Technical Data

FEATURES
Two Wire Serial Interface
+2.7 V to +5.5 V Single Supply
Low On Resistance ( $4 \Omega$ )
Low On Resistance Flatness
Low Leakage
Single 8 to 1 Matrix Switch ADG728
Dual 4 to 1 Matrix Switch ADG729
Power On Reset
Fast Switching Times
Low Power Consumption

## APPLICATIONS

Data Acquisition Systems
Communication Systems
Relay replacement
Audio and Video Switching

## GENERAL DESCRIPTION

The ADG 728 and ADG 729 are CMOS analog matrix switches with a serially controlled two wire interface. The ADG728 is an 8 channel matrix switch, while the ADG729 is a dual 4 channel matrix switches. On resistance is closely matched between switches and very flat over the full signal range. These parts can operate equally well as either Multiplexers, De-M ultiplexers or Switch arrays and the input signal range extends to the supplies.
The ADG728 and ADG729 utilize a two wire serial interface that is compatible with the $I^{2} C^{T M}$ interface standard. Both have two external address pins (A0 and A1). This allows the 2 LSB's of the 7-bit slave address to be set by the user. Four of each devices can be connected to the one bus. The ADG 728 also has a $\overline{\text { RESET }}$ pin, this should be tied high if not in use.
Each channel is controlled by one bit of an 8 bit word. This means that these devices may be used in a number of different configurations, all, any or none of the channels may be on at any one time.

## FUNCTIONAL BLOCK DIAGRAMS



On power up of the device, all switches will be in the OFF condition and the internal shift register will contain all zeros.
All channels exhibit break before make switching action preventing momentary shorting when switching channels. The ADG728 and ADG729 are available in a 16 lead TSSOP package.

## PRODUCT HIGHLIGHTS

1. Two Wire Serial Interface.
2. Single Supply Operation. The ADG 728 and ADG729 are fully specified and guaranteed with +3 V and +5 V supply rails.
3. Low $\mathrm{R}_{\mathrm{ON}}(4 \Omega)$.
4. Any configuration of switches may be on at any one time.
5. Break before make switching action.
6. Small 16 lead TSSOP package.
$1^{2} \mathrm{C}$ is a trademark of Philips Corporation.
[^0]| Parameter | B Version |  | Units | Test Conditions/Comments |
| :---: | :---: | :---: | :---: | :---: |
|  | $+25^{\circ} \mathrm{C}$ | $\text { to }+85^{\circ} \mathrm{C}$ |  |  |
| ANALOG SWITCH <br> Analog Signal Range On-Resistance ( $\mathrm{R}_{\mathrm{on}}$ ) <br> On-Resistance Match Between Channels ( $\Delta \mathrm{R}_{\text {ON }}$ ) On-Resistance Flatness ( $\mathrm{R}_{\mathrm{FLAT}(\mathrm{On})}$ ) | $\begin{aligned} & 2.5 \\ & 4 \\ & 0.75 \end{aligned}$ | $\begin{aligned} & 0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}} \\ & 4.5 \\ & 0.1 \\ & 0.4 \\ & \\ & 1.2 \end{aligned}$ | V <br> $\Omega$ typ <br> $\Omega$ max <br> $\Omega$ typ <br> $\Omega$ max <br> $\Omega$ typ <br> $\Omega$ max | $V_{S}=0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}}, \mathrm{I}_{\mathrm{S}}=10 \mathrm{~mA} \text {; }$ <br> Test Circuit 1; $\begin{aligned} & V_{S}=0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}}, I_{\mathrm{S}}=10 \mathrm{~mA} ; \\ & \mathrm{V}_{\mathrm{S}}=0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}}, I_{\mathrm{S}}=10 \mathrm{~mA} ; \end{aligned}$ |
| LEAKAGE CURRENTS <br> Source OFF Leakage IS (OFF) <br> Drain OFF Leakage ID (OFF) <br> Channel ON Leakage $I_{D}, I_{S}(O N)$ | $\begin{aligned} & \pm 0.01 \\ & \pm 0.1 \\ & \pm 0.01 \\ & \pm 0.1 \\ & \pm 0.01 \\ & \pm 0.1 \end{aligned}$ | $\begin{aligned} & \pm 0.3 \\ & \pm 0.3 \\ & \pm 0.3 \end{aligned}$ | nA typ nA max nA typ nA max nA typ nA max | $\begin{aligned} & \mathrm{V}_{\mathrm{D}}=4.5 \mathrm{~V} / 1 \mathrm{~V}, \mathrm{~V}_{\mathrm{S}}=1 \mathrm{~V} / 4.5 \mathrm{~V} \text {; } \\ & \mathrm{T}^{\text {est } C \text { ircuit } 2 ;} \\ & \mathrm{V}_{\mathrm{D}}=4.5 \mathrm{~V} / 1 \mathrm{~V}, \mathrm{~V}_{\mathrm{S}}=1 \mathrm{~V} / 4.5 \mathrm{~V} \text {; } \\ & \text { Test Circuit 2; } \\ & \mathrm{V}_{\mathrm{D}}=\mathrm{V}_{\mathrm{S}}=1 \mathrm{~V} \text {, or } 4.5 \mathrm{~V} \text {; } \\ & \text { T est Circuit 3; } \end{aligned}$ |
| LOGIC INPUTS (AO, A1) ${ }^{2}$ <br> Input High Voltage, $\mathrm{V}_{\text {INH }}$ Input Low Voltage, $\mathrm{V}_{\text {INL }}$ Input Current $\mathrm{I}_{\text {INL }}$ or $\mathrm{I}_{\text {INH }}$ <br> Cin, Input Capacitance | $\begin{aligned} & 0.005 \\ & 3 \end{aligned}$ | $\begin{array}{r} 2.4 \\ 0.8 \\ \pm 0.1 \end{array}$ | $V$ min <br> $\checkmark$ max <br> $\mu \mathrm{A}$ typ $\mu \mathrm{A}$ max pF typ |  |
| LOGIC INPUTS (SCL, SDA) ${ }^{2}$ <br> Input High Voltage, $\mathrm{V}_{\text {INH }}$ <br> Input Low Voltage, $\mathrm{V}_{\text {INL }}$ <br> $I_{\text {IN }}$, Input Leakage Current <br> $\mathrm{V}_{\text {HYST }}$, Input Hysteresis <br> $\mathrm{C}_{\text {IN }}$, Input Capacitance | $\begin{aligned} & \mathrm{TBD} \\ & 0.05 \mathrm{~V}_{\mathrm{DD}} \\ & 3 \end{aligned}$ | $\begin{aligned} & 0.7 V_{D D} \\ & V_{D D}+0.3 \\ & -0.3 \\ & 0.3 V_{D D} \\ & \pm T B D \end{aligned}$ | $V$ min <br> $V$ max <br> $V$ min <br> $\checkmark$ max <br> $\mu \mathrm{A}$ typ <br> $\mu \mathrm{A} \max$ <br> V min <br> pF typ | $\mathrm{V}_{\text {IN }}=0 \mathrm{~V}$ to $\mathrm{V}_{\mathrm{DD}}$. |
| LOGIC OUTPUT (SDA) ${ }^{2}$ Vol, Output Low Voltage |  | $\begin{aligned} & 0.4 \\ & 0.6 \end{aligned}$ | V max <br> $V$ max | $\begin{aligned} & \mathrm{I}_{\mathrm{SINK}}=3 \mathrm{~mA} \\ & \mathrm{I}_{\text {SINK }}=6 \mathrm{~mA} \end{aligned}$ |
| ```DYNAMIC CHARACTERISTICS ton toff Break-Before-M ake Time Delay, to Charge Injection Off Isolation C rosstalk -3 dB Bandwidth Cs(OFF) CD (OFF) CD},\mp@subsup{C}{S}{(ON}``` | $\begin{aligned} & 30 \\ & 21 \\ & 15 \\ & 5 \\ & -60 \\ & \\ & -80 \\ & \\ & \\ & 200 \\ & \text { T B D } \\ & \text { T B D } \\ & \text { T B D } \end{aligned}$ | $\begin{aligned} & \text { TBD } \\ & \text { TBD } \\ & 1 \end{aligned}$ | ns typ <br> ns max <br> ns typ <br> ns max <br> ns typ <br> ns min <br> pC typ <br> dB typ <br> dB typ <br> M Hz typ <br> pF typ <br> pF typ <br> pF typ | $\begin{aligned} & \mathrm{R}_{\mathrm{L}}=300 \Omega, \mathrm{C}_{\mathrm{L}}=35 \mathrm{pF} ; \\ & \mathrm{V}_{\mathrm{S}}=3 \mathrm{~V}, \mathrm{~T} \text { est Circuit 4; } \\ & \mathrm{R}_{\mathrm{L}}=300 \Omega, \mathrm{C}_{\mathrm{L}}=35 \mathrm{pF} ; \\ & \mathrm{V}_{\mathrm{S}}=3 \mathrm{~V}, \mathrm{~T} \text { est Circuit 4; } \\ & \mathrm{R}_{\mathrm{L}}=300 \Omega, \mathrm{C}_{\mathrm{L}}=35 \mathrm{pF} \\ & \mathrm{~V}_{\mathrm{S}}=\mathrm{V}_{\mathrm{S} 2}=3 \mathrm{~V}, \mathrm{~T} \text { est Circuit } 5 \\ & \mathrm{~V}_{\mathrm{S}}=2 \mathrm{~V}, \mathrm{R}_{\mathrm{S}}=0 \Omega, \mathrm{C}_{\mathrm{L}}=1 \mathrm{nF} ; \end{aligned}$ <br> Test Circuit 5; $\mathrm{R}_{\mathrm{L}}=50 \Omega, \mathrm{C}_{\mathrm{L}}=5 \mathrm{pF}, \mathrm{f}=10 \mathrm{MHz}$ <br> Test Circuit 6; $\mathrm{R}_{\mathrm{L}}=50 \Omega, \mathrm{C}_{\mathrm{L}}=5 \mathrm{pF}, \mathrm{f}=10 \mathrm{MHz} ;$ <br> Test Circuit 7; $\mathrm{R}_{\mathrm{L}}=50 \Omega, \mathrm{C}_{\mathrm{L}}=5 \mathrm{pF}, \text { Test C ircuit } 6 ;$ |
| POWER REQUIREMENTS $I_{D D}$ | 10 | T B D | $\mu \mathrm{A}$ typ $\mu \mathrm{A}$ max | $\begin{aligned} & \mathrm{V}_{D D}=+5.5 \mathrm{~V} \\ & \mathrm{D} \text { igital Inputs }=0 \mathrm{~V} \text { or } 5.5 \mathrm{~V} \end{aligned}$ |

## NOTES

${ }^{1}$ Temperature range is as follows: B Version: $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$.
${ }^{2} \mathrm{G}$ uaranteed by design, not subject to production test.

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| Parameter | $+25^{\circ} \mathrm{C}$ | $\begin{aligned} & -40^{\circ} \mathrm{C} \\ & \text { to }+85^{\circ} \mathrm{C} \end{aligned}$ | Units | Test Conditions/Comments |
| :---: | :---: | :---: | :---: | :---: |
| ANALOG SWITCH <br> Analog Signal Range On-Resistance ( $\mathrm{R}_{\mathrm{ON}}$ ) <br> On-Resistance M atch Between Channels ( $\Delta \mathrm{R}_{\text {ON }}$ ) On-Resistance Flatness ( $\mathrm{R}_{\mathrm{FLAT}(\mathrm{On})}$ ) | 4.5 0.1 | $\begin{aligned} & 0 \mathrm{~V} \text { to } V_{D D} \\ & 5 \\ & 8 \\ & \\ & 0.4 \\ & 2.5 \end{aligned}$ | V <br> $\Omega$ typ <br> $\Omega$ max <br> $\Omega$ typ <br> $\Omega$ max <br> $\Omega$ max | $\begin{aligned} & \mathrm{V}_{\mathrm{S}}=0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}}, I_{\mathrm{S}}=10 \mathrm{~mA} ; \\ & \text { T est Circuit } 1 ; \\ & \mathrm{V}_{\mathrm{S}}=0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}}, I_{\mathrm{S}}=10 \mathrm{~mA} ; \\ & \mathrm{V}_{S}=0 \mathrm{~V} \text { to } \mathrm{V}_{\mathrm{DD}}, I_{S}=10 \mathrm{~mA} ; \end{aligned}$ |
| LEAKAGE CURRENTS <br> Source OFF Leakage IS (OFF) <br> Drain OFF Leakage $I_{D}$ (OFF) <br> Channel ON Leakage $I_{D}, I_{S}(O N)$ | $\begin{aligned} & \pm 0.01 \\ & \pm 0.1 \\ & \pm 0.01 \\ & \pm 0.1 \\ & \pm 0.01 \\ & \pm 0.1 \end{aligned}$ | $\begin{aligned} & \pm 0.3 \\ & \pm 0.3 \\ & \pm 0.3 \end{aligned}$ | nA typ <br> nA max <br> nA typ <br> nA max <br> nA typ <br> nA max | $\begin{aligned} & \mathrm{V}_{\mathrm{DD}}=+3.3 \mathrm{~V} \\ & \mathrm{~V}_{\mathrm{S}}=3 \mathrm{~V} / 1 \mathrm{~V}, \mathrm{~V}_{\mathrm{D}}=1 \mathrm{~V} / 3 \mathrm{~V} ; \\ & \text { T est Circuit } 2 ; \\ & \mathrm{V}_{\mathrm{S}}=1 \mathrm{~V} / 3 \mathrm{~V}, \mathrm{~V}_{\mathrm{D}}=3 \mathrm{~V} / 1 \mathrm{~V} ; \end{aligned}$ <br> T est Circuit 2; $V_{S}=V_{D}=+1 V \text { or }+3 V \text {; }$ $\text { Test Circuit } 3 \text {; }$ |
| LOGIC INPUTS (AO, A1) ${ }^{2}$ <br> Input High Voltage, VINH Input Low Voltage, $\mathrm{V}_{\text {INL }}$ Input Current $\mathrm{I}_{\text {INL }}$ or $\mathrm{I}_{\text {INH }}$ <br> Cin, Input Capacitance | $0.005$ | $\begin{aligned} & 2.0 \\ & 0.4 \\ & \pm 0.1 \end{aligned}$ | $V$ min <br> $V$ max <br> $\mu \mathrm{A}$ typ $\mu \mathrm{A}$ max pF typ |  |
| LOGIC INPUTS (SCL, SDA) ${ }^{2}$ Input High Voltage, VINH Input Low Voltage, $\mathrm{V}_{\text {INL }}$ $I_{\text {IN }}$, Input Leakage Current $\mathrm{V}_{\text {HYST }}$, Input Hysteresis $\mathrm{C}_{\text {IN }}$, Input Capacitance | $\begin{aligned} & \text { TBD } \\ & 0.05 \mathrm{~V} \\ & 3 \end{aligned}$ | $\begin{aligned} & 0.7 V_{D D} \\ & V_{D D}+0.3 \\ & -0.3 \\ & 0.3 V_{D D} \\ & \pm T B D \end{aligned}$ | $V$ min <br> $V$ max <br> $V$ min <br> V max <br> $\mu \mathrm{A}$ typ <br> $\mu \mathrm{A} \max$ <br> $V$ min <br> pF typ | $\mathrm{V}_{\text {IN }}=0 \mathrm{~V}$ to $\mathrm{V}_{\text {DD }}$. |
| LOGIC OUTPUT (SDA) ${ }^{2}$ Vol, Output Low Voltage |  | $\begin{aligned} & 0.4 \\ & 0.6 \end{aligned}$ | $V$ max <br> $V \max$ | $\begin{aligned} & \mathrm{I}_{\operatorname{SINK}}=3 \mathrm{~mA} \\ & \mathrm{I}_{\mathrm{SINK}}=6 \mathrm{~mA} \end{aligned}$ |
| ```DYNAMIC CHARACTERISTICS2 ton t ofF Break-Before-M ake Time Delay, }\mp@subsup{t}{D}{ Charge Injection Off Isolation C rosstalk -3 dB Bandwidth C (OFF) CD (OFF) CD},\mp@subsup{C}{S}{\prime}(ON``` | $\begin{aligned} & 35 \\ & 27 \\ & 15 \\ & 5 \\ & -60 \\ & \\ & \hline-80 \\ & \\ & 200 \\ & \text { T B D } \\ & \text { T B D } \\ & \text { T B D } \end{aligned}$ | $\begin{aligned} & \text { TBD } \\ & \text { TBD } \\ & 1 \end{aligned}$ | ns typ <br> ns max <br> ns typ <br> ns max <br> ns typ <br> ns min <br> pC typ <br> dB typ <br> dB typ <br> M Hz typ <br> pF typ <br> pF typ <br> pF typ |  |
| POWER REQUIREMENTS $I_{D D}$ | 10 | T B D | $\mu \mathrm{A}$ typ $\mu \mathrm{A} \max$ | $\begin{aligned} & \mathrm{V}_{\mathrm{DD}}=+3.3 \mathrm{~V} \\ & \text { Digital Inputs }=0 \mathrm{~V} \text { or } 3.3 \mathrm{~V} \end{aligned}$ |

NOTES
${ }^{1} \mathrm{~T}$ emperature ranges are as follows: B Versions: $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$.
${ }^{2} \mathrm{G}$ uaranteed by design, not subject to production test.
Specificationssubject to change without notice.

## Preliminary Technical Data

## TIMINGCHARACTERISTICS ${ }^{1}$

| Parameter | Limit at $\mathrm{T}_{\text {MIN }}, \mathrm{T}_{\text {MAX }}$ | Units | Conditions/Comments |
| :---: | :---: | :---: | :---: |
| FSCL | 400 | kHz max | SCL Clock Frequency |
| $\mathrm{t}_{1}$ | 2.5 | $\mu \mathrm{s}$ min | SCL Cycle Time |
| $\mathrm{t}_{2}$ | 0.6 | $\mu \mathrm{s}$ min | $\mathrm{t}_{\text {HIGH }}, \mathrm{SCL}$ High Time |
| $t_{3}$ | 1.3 | $\mu \mathrm{s}$ min | tlow, SCL Low Time |
| $\mathrm{t}_{4}$ | 0.6 | $\mu \mathrm{s}$ min |  |
| $\mathrm{t}_{5}$ | 100 | $n \mathrm{n}$ min | $\mathrm{t}_{\text {SU, DAT }}$, D ata Setup Time |
| $\mathrm{t}_{6}{ }^{2}$ | 0.9 | $\mu \mathrm{s}$ max | $\mathrm{t}_{\mathrm{H}, \mathrm{dat}}$, D ata Hold Time |
|  | 0 | $\mu \mathrm{s}$ min |  |
| $\mathrm{t}_{7}$ | 0.6 | $\mu \mathrm{s}$ min | $\mathrm{t}_{\text {Su, sta }}$, Setup Time for Repeated Start |
| $\mathrm{t}_{8}$ | 0.6 | $\mu \mathrm{s}$ min | $\mathrm{t}_{\text {su, sto }}$, Stop Condition Setup Time |
| $\mathrm{t}_{9}$ | 1.3 | $\mu \mathrm{s}$ min | $\mathrm{t}_{\mathrm{BUF}}$, Bus Free Time Between a STOP Condition and a Start Condition |
| $t_{10}$ | 300 | ns max | $t_{R}$, Rise Time of both SCL and SDA when receiving |
|  | $20+0.1 C_{b}{ }^{3}$ | ns min |  |
| $\mathrm{t}_{11}$ | 250 | ns max | $t_{F}, F$ all Time of SDA when receiving |
|  | 300 | ns max | $\mathrm{t}_{\mathrm{F}}$, Fall Time of both SCL and SDA when transmitting |
|  | $20+0.1 C_{b}{ }^{3}$ | ns min |  |
| $C_{b}$ | 400 | pF max | Capacitive Load for Each Bus Line |
| $\mathrm{t}_{\text {SP }}{ }^{4}$ | 50 | ns max | Pulse width of spike suppressed |

NOTES
${ }^{1}$ See Figure 1.
${ }^{2}$ A master device must provide a hold time of at least 300 ns for the SDA signal (referred to the $V_{1 H}$ min of the SCL signal) in order to bridge the undefined region of SCL's falling edge.
${ }^{3} \mathrm{C}_{\mathrm{b}}$ is the total capacitance of one bus line in pF . $\mathrm{t}_{\mathrm{R}}$ and $\mathrm{t}_{\mathrm{F}}$ measured between $0.3 \mathrm{~V}_{D D}$ and $0.7 \mathrm{~V}_{D D}$.
${ }^{4}$ Input filtering on both the SCL and SDA inputs suppress noise spikes which are less than 50 ns .
Specificationssubject to change without notice.


Figure 1. 2-Wire Serial Interface Timing Diagram.

## Preliminary Technical Data

## PIN FUNCTION DESCRIPTION

| ADG728 | ADG 729 | Mnemonic | Function |
| :---: | :---: | :---: | :---: |
| 1 | 1 | SCL | Serial Clock Line. This is used in conjunction with the SDA line to clock data into the 16 -bit input shift register. Clock rates of up to $400 \mathrm{kbit} / \mathrm{s}$ can be accommodated with this 2 -wire serial interface. |
| 2 | - | $\overline{\mathrm{R}} \overline{\mathrm{E}} \overline{\mathrm{E}} \overline{\mathrm{T}}$ | Active low control input that clears the input register and turns all switches to the OFF condition. |
| 3 | 3 | SD A | Serial Data Line. This is used in conjunction with the SCL line to clock data into the 8 -bit input shift register during the write cycle and used to read back 1 byte of data during the read cyle. It is a bidirectional open-drain data line which should be pulled to the supply with an external pull-up resistor. |
| 4,5,6,7 | 4,5,6,7 | SXX | Source. May be an input or output. |
| 8 | 8,9 | D X | Drain. M ay be an input or output. |
| 9,10,11,12 | 10,11,12,13 | SXX | Source. May be an input or output. |
| 13 | 14 | $V_{\text {D }}$ | Power Supply Input. These parts can be operated from a supply of +2.5 V to +5.5 V . |
| 14 | 15 | GND | Ground reference. |
| 15 | 2 | A 1 | Address Input. Sets the 2nd Least Significant bit of the 7 bit slave address. |
| 16 | 16 | A 0 | Address Input. Sets the Least Significant bit of the 7 bit slave address. |

PIN CONFIGURATIONS


ORDERING GUIDE

| Model | Temperature Range | Package Description | Package Option |
| :--- | :--- | :--- | :--- |
| ADG 728BRU | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | Thin Shrink Small Outline Package (TSSOP) | RU-16 |
| AD G 729BRU | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | Thin Shrink Small Outline Package (TSSOP) | $\mathrm{RU}-16$ |

## TERMINOLOGY

$R_{\text {ON }}$
$R_{\text {FLAT(ON })}$

IS (OFF) Source leakage current with the switch "OFF."
$I_{D}(O F F) \quad$ Drain leakage current with the switch "OFF."
$I_{D}, I_{S}(O N) \quad$ Channel leakage current with the switch "ON."
$V_{D}\left(V_{S}\right)$
Analog voltage on terminals $D, S$.
"OFF" switch source capacitance.
"OFF" switch drain capacitance.
$C_{D}$ (OFF) "ON" switch capacitance.
Delay between applying the digital control input and the output switching on. See test circuit 4.
$t_{\text {OFF }}$

Off Isolation A measure of unwanted signal coupling through an "OFF" switch.
Charge A measure of the glitch impulse transferred Injection from the digital input to the analog output during switching.
$B$ andwidth The frequency at which the output is attenuated by -3 dBs .
On Response The Frequency response of the "ON" switch.

On Loss The voltage drop across the "ON" switch
seen on the On Response vs. Frequency plot
as how many dBs the signal is away from
seen on the $O n$ Response vs. Frequency plot
as how many dB s the signal is away from 0 dB .
$V_{\text {INL }} \quad$ Maximum input voltage for logic " 0 ".
$V_{\text {INH }} \quad M$ inimum input voltage for logic " 1 ".
$I_{\text {INL }}\left(I_{\text {INH }}\right) \quad$ Input current of the digital input.
IDD Positive supply current.
Delay between applying the digital control input and the output switching off. A measure of the glitch impulse transferred
from the digital input to the analog output

## ABSOLUTE MAXIMUM RATINGS ${ }^{1}$

( $\mathrm{T}_{\mathrm{A}}=+25^{\circ} \mathrm{C}$ unless otherwise noted)
$V_{D D}$ to GND
Analog, Digital Inputs ${ }^{2}$
Peak Current, S or D
(Pulsed at $1 \mathrm{~ms}, 10 \%$ Duty Cycle max)
Continuous Current, each S
Continuous Current D, ADG 729 80mA
Continuous Current D, ADG728 120mA
Operating Temperature Range Industrial (B Version)
Storage Temperature Range
Junction Temperature
$-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$
$-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
$+150^{\circ} \mathrm{C}$

| SOP Package, Power Dissipation | mW |
| :---: | :---: |
| $\theta_{\text {JA }}$ Thermal Impedance | $150.4{ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| $\theta_{\text {Jc }}$ Thermal Impedance | $27.6{ }^{\circ} \mathrm{C} / \mathrm{W}$ |
| Lead Temperature, Soldering |  |
| Vapor Phase (60 sec) | $+215^{\circ} \mathrm{C}$ |
| Infrared (15 sec) | $+220^{\circ} \mathrm{C}$ |
| ESD | TBDkV |
| NOTES |  |
| ${ }^{1}$ Stresses abovethoselisted under "AbsoluteM aximum damageto thedevice. T hisisa stress rating only and fu at theseor any other conditions above thoselisted in specification is not implied. Exposure to absolute max extended periodsmay affect devicereliability. Only on be applied at any onetime. | ycausepermanent ation of thedevice al sections of this ing conditions for ximum ratingmay |
| ${ }^{2} O$ vervoltages at IN, $S$ or $D$ will beclamped by internal d to the maximum ratings given. | tshould belimited |

mW
$150.4^{\circ} \mathrm{C} / \mathrm{W}$
$27.6^{\circ} \mathrm{C} / \mathrm{W}$
$+215^{\circ} \mathrm{C}$
$+220^{\circ} \mathrm{C}$
TBD kV
${ }^{1}$ Stresses abovethoselisted under "AbsoluteM aximum Ratings" may causepermanent
 theseor any other conditions abovethoselisted in theoperational sections of this extended periodsmayaffectdevicereliability. Onlyoneabsolutemaximumratingmay be applied at any onetime.
to the maximum ratings given.

## CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the AD G 728/AD G 729 features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.


## Preliminary Technical Data

## GENERAL DESCRIPTION

The ADG 728 and ADG 729 are serially controlled, 8 channel and dual 4 channel matrix switches respectively. While providing the normal multiplexing and demultiplexing functions, these devices also provide the user with some more flexibility as to where their signal may be routed. Each bit of the serial word corresponds to one switch of the device. A logic ' 1 ' in the particular bit position turns on the switch, while a logic ' 0 ' turns the switch off. Because each switch is independently controlled by an individual bit, this provides the option of having any, all or none of the switches ON. This feature may be particularly useful in the demultiplexing application where the user may wish to direct one signal from the drain to a number of outputs (sources). Care must be taken, however, in the multiplexing situation where a number of inputs may be shorted together, (only seperated by the small on resistance of the switch).

## POWER ON RESET

On power up of the device, all switches will be in the OFF condition and the internal shift register is filled with zeros and will remain so until a valid write takes place.

## SERIAL INTERFACE <br> 2-WIRE SERIAL BUS

The ADG728/ADG729 are controlled via an $I^{2} \mathrm{C}$ compatible serial bus. These parts are connected to this bus as a slave device (no clock is generated by the multiplexer)
The ADG 728/ADG 729 have different 7-bit slave addresses. The five MSBs of the ADG728 are 10011, while the MSB's of the ADG 729 are 10001 and the two LSBs are determined by the state of the A0 and A1 pins.
The 2-wire serial bus protocol operates as follows:

1. The master initiates data transfer by establishing a START condition which is when a high to low transition on the SDA line occurs while SCL is high. The following byte is the address byte which consists of the 7-bit slave address followed by a $\mathrm{R} / \overline{\mathrm{W}}$ bit (this bit determines whether data will be read from or written to the slave device).
The slave whose address corresponds to the transmitted address responds by pulling the SDA line low during the ninth clock pulse (this is termed the Acknowledge bit). At this stage, all other devices on the bus remain idle while the selected device waits for data to be written to or read from its serial register. If the $\mathrm{R} / \overline{\mathrm{W}}$ bit is high, the master will read from the slave device. However, if the $R / \overline{\mathrm{W}}$ bit is low, the master will write to the slave device.
2. Data is transmitted over the serial bus in sequences of nine clock pulses (eight data bits followed by an Acknowledge bit). The transitions on the SDA line must occur during the low period of SCL and remain stable during the high period of SCL.
3) When all data bits have been read or written, a STOP condition is established by the master. A STOP condition is defined as a low to high transition on the SDA line while SCL is high. In Write mode, the master will pull the SDA line high during the 10th clock pulse to establish a STOP condition. In Read mode, the master will issue a No Acknowledge for the 9th clock pulse (i.e. the SDA line remains high). The master will then bring the SDA line low before the 10th clock pulse and then high during the 10th clock pulse to establish a STOP condition.
See Figure 3 below for a graphical explanation of the serial interface.

A repeated write function gives the user flexibility to update the matrix switch a number of times after addressing the part only once. During the write cycle, each data byte will update the configuration of the switches. For example, after the matrix switch has acknowledged its address byte, and receives one data byte, the switches will update after the data byte, if another data byte is written to the matrix switch while it is still the addressed slave device, this data byte will also cause an switch configuration update. Repeat read of the matrix switch is also allowed.

## INPUT SHIFT REGISTER

The input shift register is 8 -bits wide. Figure 2 illustrates the contents of the input shift register. Data is loaded into the device as an 8 -bit word under the control of a serial clock input, SCL. The timing diagram for this operation is shown in Figure 1. The 8 -bit word consists of 8 data bits each controlling one switch. M SB (Bit 7) is loaded first.


Figure 2. ADG 728/ADG 729 Input Shift Register Contents

## WRITE OPERATION

When writing to the ADG728/ADG729, the user must begin with an address byte and $\mathrm{R} / \overline{\mathrm{W}}$ bit, after which the switch will Acknowledge that it is prepared to receive data by pulling SDA low. This address byte is followed by the 8 -bit word. The write operations for each matrix switch are shown in the figures below.


Figure 3. ADG728 Write Sequence


Figure 4. ADG 729 Write Sequence

## READ OPERATION

When reading data back from the ADG728/ADG729, the user must begin with an address byte and $R / \overline{\mathrm{W}}$ bit, after which the matrix switch will Acknowledge that it is prepared to transmit data by pulling SDA low. The readback operation is a single byte which consists of the 8 data bits in the input register. The read operations for each part are shown in the figures below.


Figure 5. ADG728 Readback Sequence


Figure 6. ADG729 Readback Sequence

## TestCircuits



Test Circuit 1. On Resistance.


Test Circuit 2. Off Leakage.


Test Circuit 3. On Leakage.


Test Circuit 4. Switching Times.


Test Circuit 5. Charge Injection.


TestCircuit6. Off Isolation, Bandwidth.

## OUTLINE DIMENSIONS

Dimensions shown in inches and (mm).

16-Lead TSSOP
(RU-16)



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